



Future Normal in Semiconductor

2025-02-13(목), 09:00-10:45

좌장: 추후업데이트 예정

K. Memory (Design & Process Technology) 분과

[TA1-K] DRAM Application

<p>초청</p> <p>TA1-K-1</p> <p>09:00-09:30</p>	<p>조현보 대표 (알세미)</p>
<p>TA1-K-2</p> <p>09:30-09:45</p>	<p>Development of an Automated DTCO Methodology for Optimized DRAM Sense Amplifier Design</p> <p>Sueyeon Kim¹, Jaeweon Kang², and Jongwook Jeon¹</p> <p>¹Department of Electrical and Computer Engineering, Sungkyunkwan University, ²Department of Semiconductor Convergence Engineering, Sungkyunkwan University</p>
<p>TA1-K-3</p> <p>09:45-10:00</p>	<p>Overcoming Leakage Challenges in Vertical Gate-all Around Architectures : A Pathway to High-Performance 3D DRAM</p> <p>Seong Hun Yoon¹, Jae Hyun Park², Jung Ho Lee², and Jae Kyeong Jeong^{1,2}</p> <p>¹Department of Display Science and Engineering, Hanyang University, ² Department of Artificial Intelligence Semiconductor Engineering, Hanyang University</p>
<p>TA1-K-4</p> <p>10:00-10:15</p>	<p>Understanding the Abnormal Capacitance of Ferroelectric HZO near Morphotropic Phase Boundary: Excellent Candidate for DRAM and Capacitive Memory Array with Non-destructive Read Operation</p> <p>M. Habibi¹, A. Kashir², S. Oh, H. Jang, and H. Hwang</p> <p>¹POSTECH, ²Ferroelectric Memory GmbH</p>
<p>TA1-K-5</p> <p>10:15-10:30</p>	<p>Simulation of Capacitorless Dynamic Random-Access Memory based on GAA JLFET with Vertically Stacked Storage Layer and Underlapped Gate Structure</p> <p>Won Suk Koh, Sang Ho Lee, Jin Park, Min Seok Kim, Seung Ji Bae, Jeong Woo Hong, Gang San Yun, and In Man Kang</p> <p>School of Electronic and Electrical Engineering, Kyungpook National University</p>
<p>TA1-K-6</p> <p>10:30-10:45</p>	<p>A Study on the Cb/Cs Ratio in 3.5F² DRAM Cell Array</p> <p>Hyeok Je Jeong¹, Kwang Ryeol Kim¹, Chai Rok Lim¹, Yong Soo Kim², Dae Young Kim³, Jae Hyun Lee⁴, and Gi Yeol Yun¹</p> <p>¹Taesung Environmental Research Institute, ²University of Ulsan, ³Osan University, ⁴Pusan National University</p>